

## **Subject:** Testability and Accessibility

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### **1. Testability**

The testability of ICT testing is based on the following conditions:

- a. Limitation of Tester
- b. Property of UUT's circuit network design
- c. PCB layout of UUT
- d. Capability of fixture's fabrication

### **2. Accessibility**

The accessibility of fixture is the most important factor to improve testability of ICT testing. Accessibility is related to the PCB layout of UUT and the capability of fixture's fabrication.

To improve the accessibility of fixture, it's necessary to understand the DFT (Design for Test) rule of PCB layout. (Described in TP-7.03)

The basic requirement and limitation to build a fixture for UUT includes,

- a. Every single trace (net) need at lease one probe.
- b. The accessibility of testing after SMT process and testing after DIP process could be different. The probe tip could be different also.
- c. The limitation of probe is 50 mil.
- d. Fixture can be double side access.
- e. Definition of "Test Point" could be,
  - Test Pad
  - Dip component leg
  - Through Hole
  - Via Hole